Search Notes



	Applicant(s)/Patent under Reexamination
10/570 700	

2193

10/578,780 TANOUE ET AL.

Examiner Art Unit

Tan V. Mai

SEARCHED					
Class	Subclass	Date	Examiner		
708	209	9/10/2008	MAI		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
708	209	9/10/2008	MAJ	
interferer	t search (see nce search ntout)	9/10/2008	MAI	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	9/10/2008	MAI	